

for selecting a second of the beams having a second wavelength to produce a second scan pattern, the scan patterns having a different number of scan lines, and the scan pattern generator being operative for scanning the selected scan pattern over the indicia to be read.

51. (Amended) The scanner according to claim 50, wherein the first [laser beam has a] wavelength [of] is 670 nm, and wherein the second [laser beam has a] wavelength [of] is 630 nm.

64. (Amended) A method of reading indicia having parts of different light reflectivity, comprising the steps of:

- a) producing a plurality of light beams of different wavelengths;
- b) selecting a first of the beams having a first wavelength to produce a first scan pattern, and selecting a second of the beams having a second wavelength to produce a second scan pattern, the scan patterns having a different number of scan lines; and
- c) scanning the selected scan pattern over the indicia to be read.

66. (Amended) The method according to claim 65, wherein the first [laser beam has a] wavelength [of] is 670 nm, and wherein the second [laser beam has a] wavelength [of] is 630 nm.

REMARKS

The originally-filed application identified the immediately preceding application, i.e., U.S. Serial No. 08/405,585. This amendment competes the lineage of the '585 application.